

Legacy Device: *Motorola 12509, 12511, 12513*

These devices are two-modulus prescalers which will divide by 5 and 6, 8 and 9, respectively. A MECL-to-MTTL translator is provided to interface directly with the Motorola MC12014 Counter Control Logic. In addition, there is a buffered clock input and MECL bias voltage source.

- ML12509 480 MHz ($\div 5/6$), ML12511 550 MHz ($\div 8/9$), ML12513 550 MHz ($\div 10/11$)
- MECL to MTTL Translator on Chip
- MECL and MTTL Enable Inputs
- 5.0 or -5.2 V Operation*
- Buffered Clock Input — Series Input RC Typ, 20 Ω and 4.0 pF
- VBB Reference Voltage
- 310 mW (Typ)

* When using a 5.0 V supply, apply 5.0 V to Pin 1 (VCCO), Pin 6 (MTTL VCC), Pin 16 (VCC), and ground Pin 8 (VEE). When using -5.2 V supply, ground Pin 1 (VCCO), Pin 6 (MTTL VCC), and Pin 16 (VCC) and apply -5.2 V to Pin 8 (VEE). If the translator is not required, Pin 6 may be left open to conserve DC power drain.

MAXIMUM RATINGS

Characteristic	Symbol	Rating	Unit
(Ratings above which device life may be impaired)			
Power Supply Voltage (VCC = 0)	VEE	-8.0	Vdc
Input Voltage (VCC = 0)	Vin	0 to VEE	Vdc
Output Source Current Continuous	IO	< 50	mAdc
Surge		< 100	
Storage Temperature Range	Tstg	-65 to 175	C

(Recommended Maximum Ratings above which performance may be degraded)

Operating Temperature Range	TA	-55 to 125	C
DC Fan-Out (Note 1) (Gates and Flip-Flops)	n	70	—

NOTES: 1. AC fan-out is limited by desired system performance.

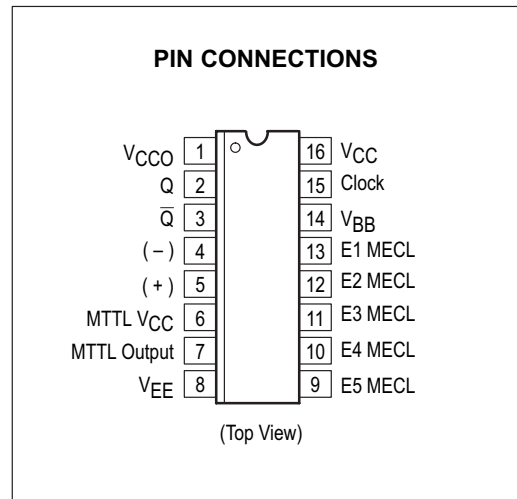
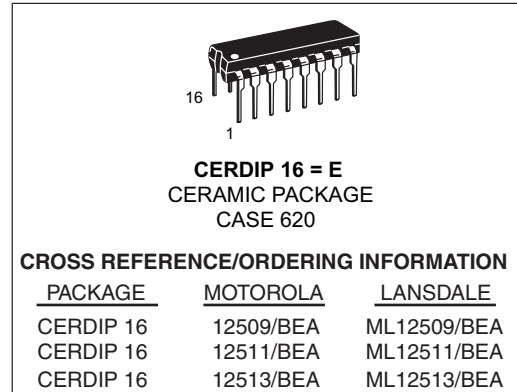
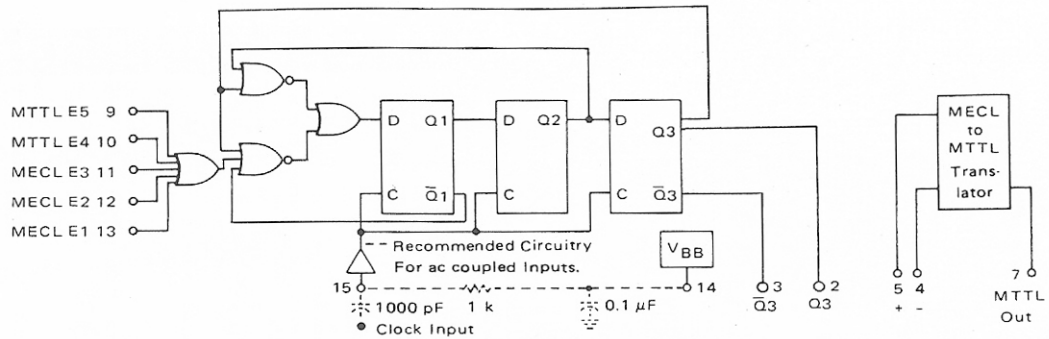
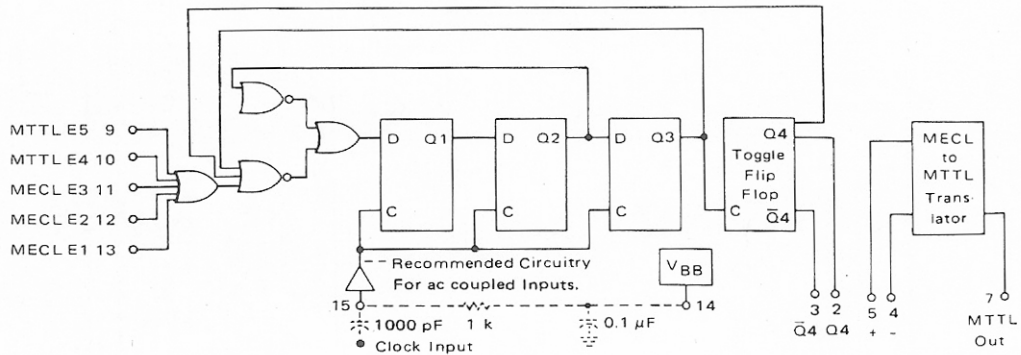


FIGURE 1 - LOGIC DIAGRAMS

ML12509



ML12511



ML12513

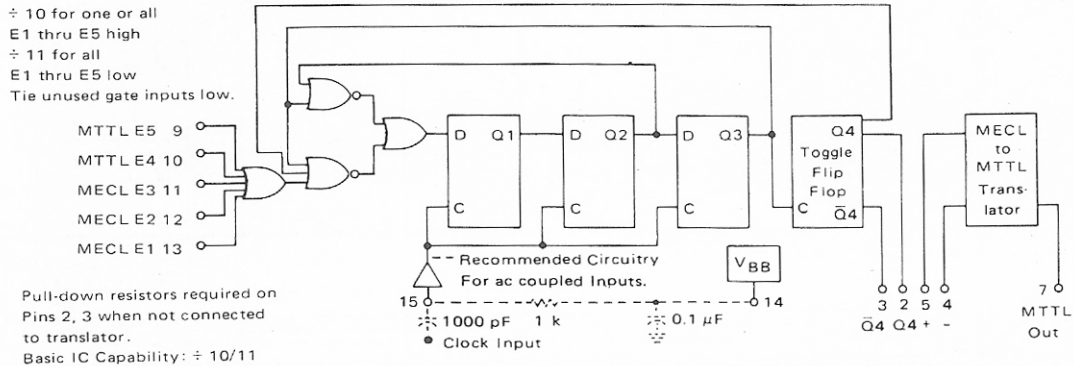
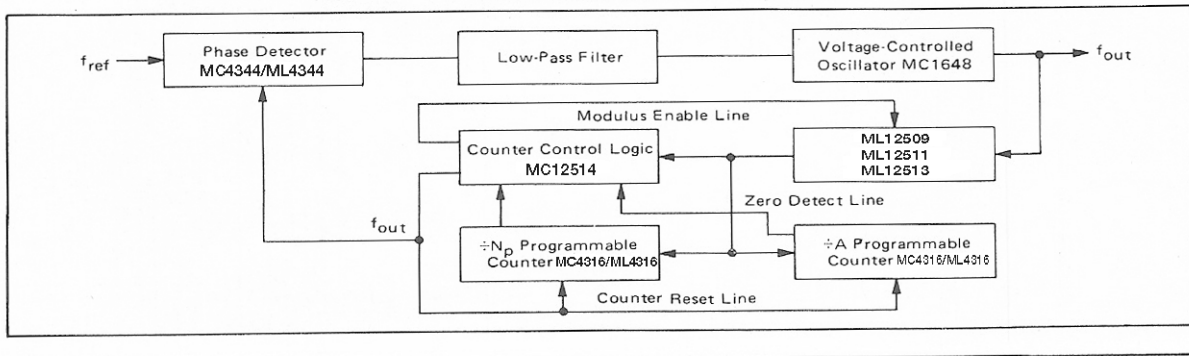


FIGURE 2 - TYPICAL FREQUENCY SYNTHESIZER APPLICATION



ELECTRICAL CHARACTERISTICS

Test Temperature	Test Voltage Values (Volts)												Test Current Values (mA)					
	V _{IH}	V _{IL}	V _{IHA}	V _{ILA}	V _{IHB}	V _{ILB}	V _{IHT}	V _{ILT}	V _{VEE}	V _{VCC}	V _{IHmin}	V _{ILmin}	V _{ILL}	VEEL	V _{VCCA}	I _L	I _{OL}	I _{OH}
T _A = 25 °C	+2.4	+0.5	+3.895	+3.525	+4.22	+3.11	+2.0	+0.8	0.0	+5.0	+1.15	+0.215	-3.0	-3.0	+2.0	-0.25	+16	-0.4
T _A = 125 °C	+2.4	+0.5	+4.0	+3.6	+4.37	+3.14	+2.0	+0.8	0.0	+5.0	+1.27	+0.26	-3.0	-3.0	+2.0	-0.25	+16	-0.4
T _A = -55 °C	+2.4	+0.5	+3.745	+3.5	+4.12	+3.04	+2.0	+0.8	0.0	+5.0	+1.02	+0.165	-3.0	-3.0	+2.0	-0.25	+16	-0.4

Symbol	Parameter	Limits						Units	TEST VOLTAGE APPLIED TO PINS BELOW										
		+ 25 °C		+ 125 °C		- 55 °C			Pinouts referenced are for DIL package, check Pin Assignments Output Load = 100 Ω to + 3.0 V										
		Subgroup 1		Subgroup 2		Subgroup 3			V _{IH}	V _{IL}	V _{IHA/B}	V _{ILA/B}	V _{VCC}	V _{VEE}	C _{P1}	I _{OH/OL}	I _L	P.U.T.	
V _{OH1}	Output Voltage High	4.03	4.22	4.135	4.37	3.88	4.12	V	9, 10	9, 10	11 - 13	11 - 13	1, 16	8	15			2, 3 (Note 2)	
V _{OH2}	Output Voltage High	2.70	4.5	3.00	4.5	2.40	4.5	V			5	4	6	8		7 I _{OH}		7	
V _{OL1}	Output Voltage Low	3.11	3.44	3.14	3.515	3.04	3.405	V	9, 10	9, 10	11 - 13	11 - 13	1, 16	8	15			2, 3 (Note 2)	
V _{OL2}	Output Voltage Low	0.10	0.80	0.10	0.66	0.10	1.00	V			4	5	6	8		7 I _{OL}		7	
V _{OHA}	Output Voltage High	4.01	4.5	4.115	4.5	3.86	4.5	V			9, 10	11 - 13	1, 16	8	15			2, 3 (Note 3)	
V _{OLA}	Output Voltage Low	3.11	3.46	3.14	3.595	3.04	3.425	V			9, 10	11 - 13	1, 16	8	15			2, 3 (Note 3)	
V _{BB1}	Reference Bias Supply Voltage	3.67		3.87				V											
I _{OS}	Output Short Circuit Current	- 65		- 20		- 65		- 20	mA	7	5	4	6	8				7	
I _{CC1}	Power Supply Current	- 80		- 80		- 88			mA										
I _{CC2}	Power Supply Current	5.2		5.2		5.2			mA	4	5	6	8					6	

1. Power Supply Voltage = 5.0 V, Power Supply Voltage = - 5.2 V is guaranteed but not tested.
2. See Sequence Table 1.
3. See Sequence Table 2.

ELECTRICAL CHARACTERISTICS

Test Temperature	Test Voltage Values (Volts)													Test Current Values (mA)				
	V _{IH}	V _{IL}	V _{IHA}	V _{ILA}	V _{IHB}	V _{ILB}	V _{IHT}	V _{ILT}	V _{EE}	V _{CC}	V _{IHmin}	V _{ILmin}	V _{IILL}	V _{EEL}	V _{CCA}	I _L	I _{OL}	I _{OH}
T _A = 25 °C	+ 2.4	+ 0.5	+ 3.895	+ 3.525	+ 4.22	+ 3.11	+ 2.0	+ 0.8	0.0	+ 5.0	+ 1.15	+ 0.215	- 3.0	- 3.0	+ 2.0	- 0.25	+ 16	- 0.4
T _A = 125 °C	+ 2.4	+ 0.5	+ 4.0	+ 3.6	+ 4.37	+ 3.14	+ 2.0	+ 0.8	0.0	+ 5.0	+ 1.27	+ 0.26	- 3.0	- 3.0	+ 2.0	- 0.25	+ 16	- 0.4
T _A = -55 °C	+ 2.4	+ 0.5	+ 3.745	+ 3.5	+ 4.12	+ 3.04	+ 2.0	+ 0.8	0.0	+ 5.0	+ 1.02	+ 0.165	- 3.0	- 3.0	+ 2.0	- 0.25	+ 16	- 0.4

Symbol	Parameter	Limits						Units	TEST VOLTAGE APPLIED TO PINS BELOW									
		+ 25 °C		+ 125 °C		- 55 °C			Pinouts referenced are for DIL package, check Pin Assignments Output Load = 100 Ω to + 3.0 V									
		Subgroup 1		Subgroup 2		Subgroup 3			V _{IH}	V _{IL}	V _{IHA/B}	V _{ILA/B}	V _{CC}	V _{EE}	P.U.T.			
I _{NH1}	Input Current High		250		400		400	μA	9, 10	11 - 13, 15		1, 16	8	11, 12, 13, 15				
I _{NH2}	Input Current High	2.0	6.0	2.0	6.4	1.7	6.0	mA		4, 5	4, 5	6	8	4, 5				
I _{NH3}	Input Current High	1.0	3.0	1.0	3.6	0.7	3.0	mA		4	5	6	8	5				
I _{NH4}	Input Current High		100		100		100	μA	9, 10		1, 16	8	8	9, 10				
I _{NI1}	Input Current Low	- 10		- 10		- 10		μA			1, 16	8, 15, 11 - 13	8	11, 12, 13, 15				
I _{NI1}	Input Current Low	- 1.6		- 1.6		- 1.6		mA	9, 10		1, 16	8	8	9, 10				

1. Power Supply Voltage = 5.0 V, Power Supply Voltage = - 5.2 V is guaranteed but not tested.

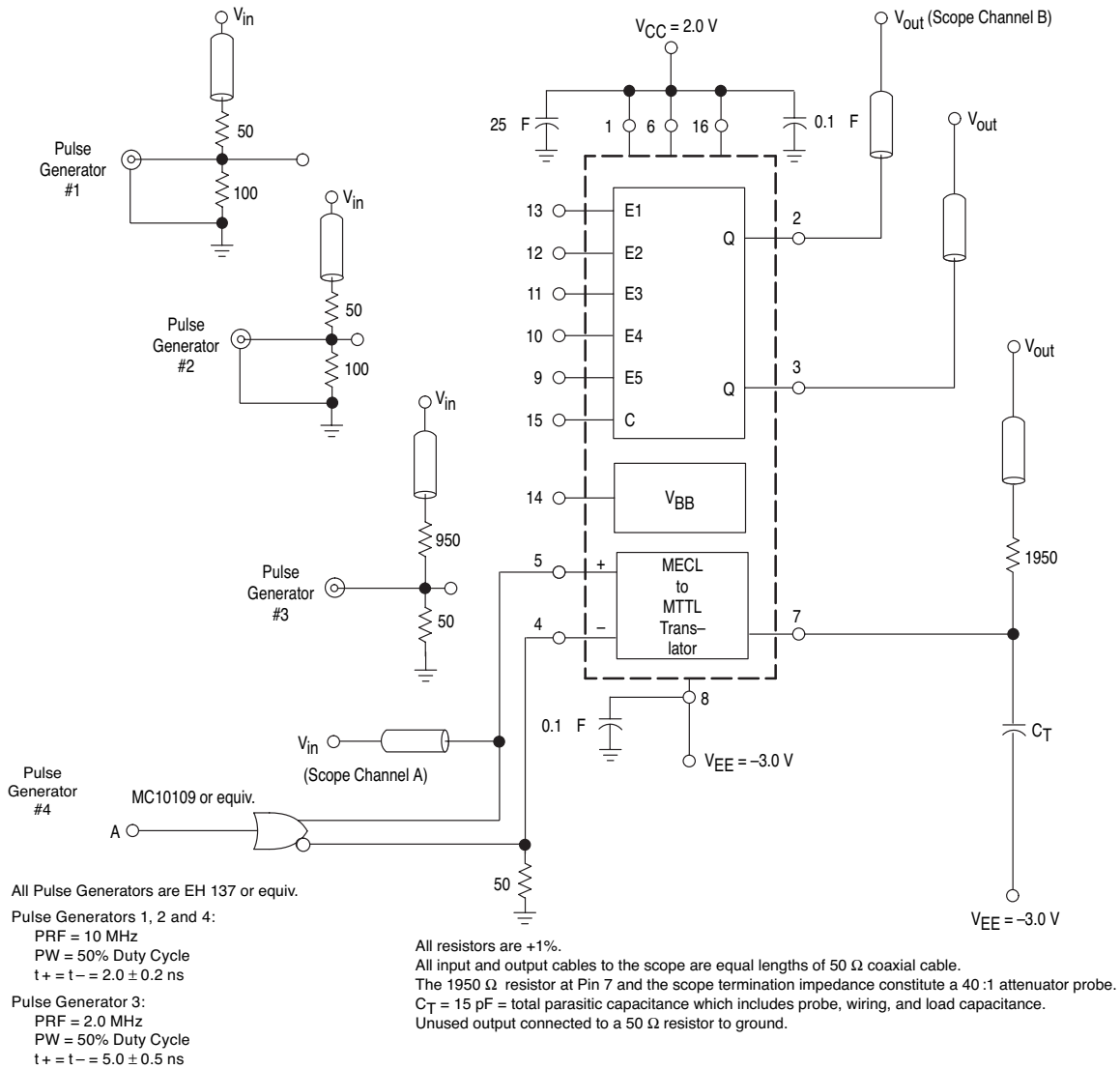
* **ELECTRICAL CHARACTERISTICS:** This device is designed to meet the dc specifications shown in the test table after thermal equilibrium has been established. Outputs are terminated through a 100 Ω resistor to + 3.0 V.

Test Temperature	Test Voltage Values (Volts)										Test Current Values (mA)								
	V _{IH}	V _{IL}	V _{IHA}	V _{ILA}	V _{IHB}	V _{ILB}	V _{IHT}	V _{ILT}	V _{EE}	V _{CC}	V _{IHmin}	V _{ILmin}	V _{ILL}	VEEL	V _{OUT}	V _{CCA}	I _L	I _{OL}	I _{OH}
T _A = 25 °C	+2.4	+0.5	+3.895	+3.525	+4.22	+3.11	+2.0	+0.8	0.0	+5.0	+1.15	+0.215	-3.0	-3.0		+2.0	-0.25	+16	-0.4
T _A = 125 °C	+2.4	+0.5	+4.0	+3.6	+4.37	+3.14	+2.0	+0.8	0.0	+5.0	+1.27	+0.26	-3.0	-3.0		+2.0	-0.25	+16	-0.4
T _A = -55 °C	+2.4	+0.5	+3.745	+3.5	+4.12	+3.04	+2.0	+0.8	0.0	+5.0	+1.02	+0.165	-3.0	-3.0		+2.0	-0.25	+16	-0.4

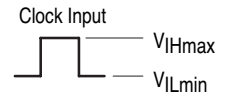
SWITCHING CHARACTERISTICS

Symbol	Parameter	Limits						Units	TEST VOLTAGE APPLIED TO PINS BELOW														
		+ 25 °C		+ 125 °C		- 55 °C			Pinouts referenced are for DIL package, check Pin Assignments Output Load = 100 Ω to + 3.0 V														
		Subgroup 9		Subgroup 10		Subgroup 11			V _{ILL}	V _{ILmin}	V _{IN}	V _{OUT}	V _{CCA}	VEEL	P.U.T.	V _{ILL}	V _{ILmin}	V _{IN}	V _{OUT}	V _{CCA}	VEEL	P.U.T.	
	Functional Parameters: (Fig. 5)																						
t _{PHH}	Propagation Delay (15+2+)	8.1		9.4		8.1		ns	9, 10	11 - 13	15	2, 3	1, 6, 16	8	2, 3								2, 3
t _{PHH}	Propagation Delay (5+ 7+)	8.1		9.4		8.1		ns	9, 10	11 - 13	15	2, 3	1, 6, 16	8	2, 3								2, 3
t _{PLL}	Propagation Delay (15+ 2-)	7.5		8.7		7.5		ns	9, 10	11 - 13	15	2, 3	1, 6, 16	8	7								7
t _{PLL}	Propagation Delay (5- 7-)	6.5		7.6		6.5		ns	9, 10	11 - 13	15	2, 3	1, 6, 16	8	7								7
t _{Setup 1}	Setup Time MECL	5.0		5.0		5.0		ns	V _{ILL}	V _{ILmin}	V _{IN}	V _{OUT}	V _{CCA}	VEEL	P.U.T.								
t _{Setup 2}	Setup Time MTTL	5.0		5.0		5.0		ns	9, 10	11 - 13	9 - 13												
t _{Rel 1}	Release Time MECL	5.0		5.0		5.0		ns	9, 10	11 - 13	9 - 13												
t _{Rel 2}	Release Time MTTL	5.0		5.0		5.0		ns	9, 10	11 - 13	9 - 13												
f _{max +5/6}	(Fig 6) Toggle Frequency ML12509	480		440		500		MHZ	V _{ILL}	V _{ILmin}	V _{IN}	V _{OUT}	V _{CCA}	VEEL	P.U.T.								
-8/9	ML12511	500		550		550		MHZ			15	2	1, 6, 16	8 - 13	2								2
+10/11	ML12513	550		540		600		MHZ			15	2	1, 6, 16	8 - 13	2								2

Figure 5. AC Test Circuit



- NOTES:**
1. Test outputs of the device must be tested by sequencing through the truth table. All input, power supply and ground voltages must be maintained between tests. The clock input is the waveform shown.
 2. In addition to meeting the output levels specified, the device must divide by 5 or 8 during this test. The clock input is the waveform shown.
 3. In addition to meeting the output levels specified, the device must divide by 6 or 9 during this test. The clock input is the waveform shown.



Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50 Ω resistor to -2.0 V. Test procedures are shown for only one gate. The other gates are tested in the same manner.

Figure 3. AC Voltage Waveforms

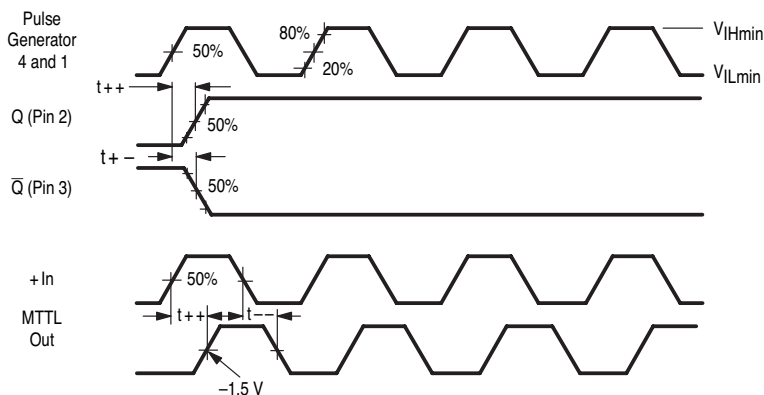


Figure 4. Setup and Release Time Waveforms

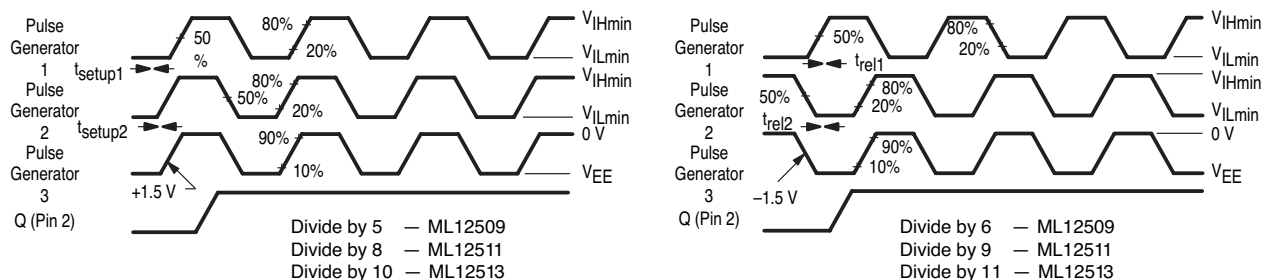
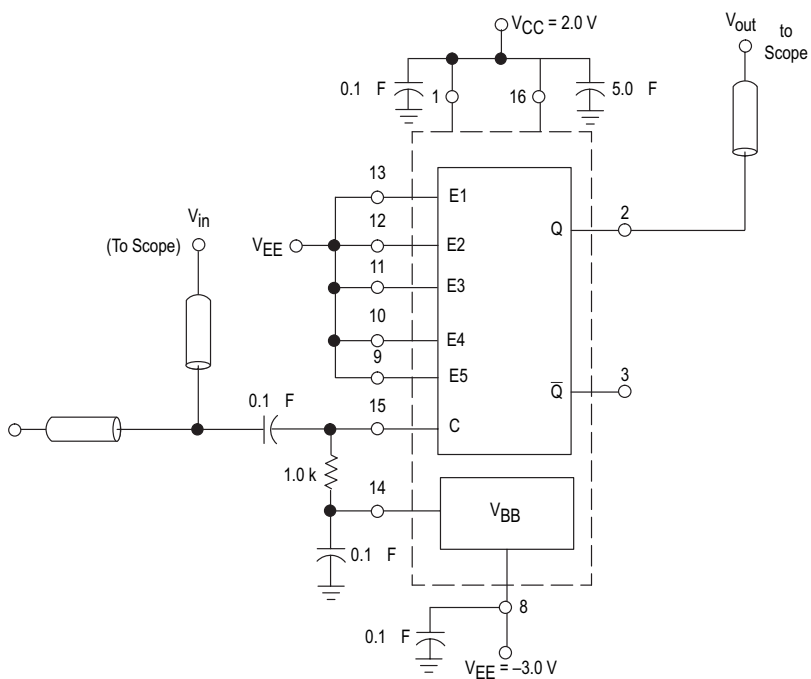


Figure 6. Maximum Frequency Test Circuit



Unused output connected to a 50 Ω resistor to ground

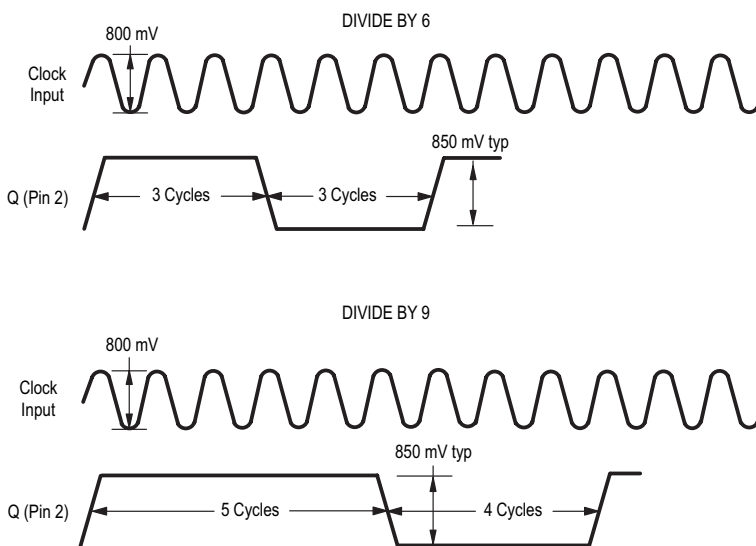
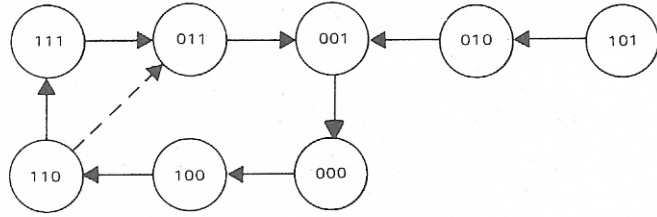


FIGURE 7 – STATE DIAGRAM

DIVIDE BY 5/6 (ML12509)

	Q1	Q2	Q3
Enable = 0	1	1	1
	0	1	1
	0	0	1
	0	0	0
	1	0	0
Enable = 1	1	1	0

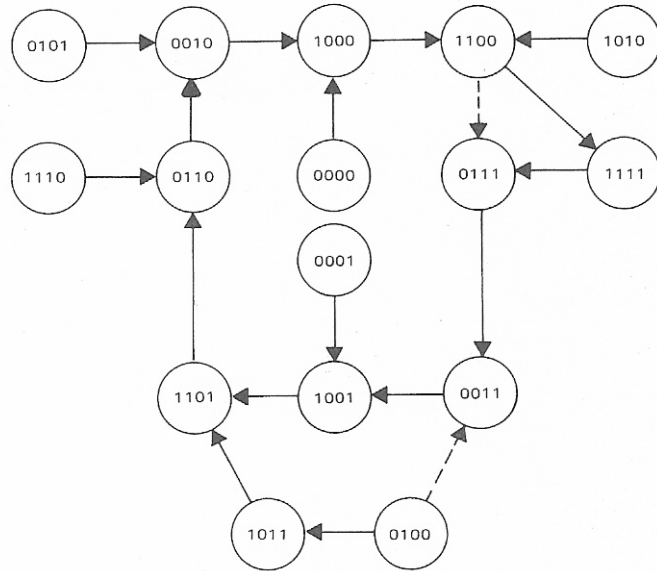
--- Enable = 1



DIVIDE BY 8/9 (ML12511)

	Q1	Q2	Q3	Q4
Enable = 0	1	1	1	1
	0	1	1	1
	0	0	1	1
	1	0	0	1
	1	1	0	1
	0	1	1	0
	0	0	1	0
	1	0	0	0
Enable = 1	1	1	0	0

--- Enable = 1



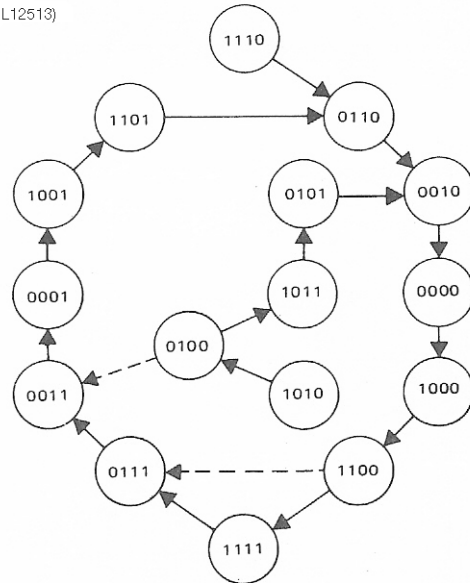
DIVIDE BY 10/11 (ML12513)

	Q1	Q2	Q3	Q4
Enable = 0	1	1	1	1
	0	1	1	1
	0	0	1	1
	0	0	0	1
	1	0	0	1
	1	1	0	1
	0	1	1	0
	0	0	1	0
	0	0	0	0
	1	0	0	0
Enable = 1	1	1	0	0

NOTES:

--- Enable = 1.

The State of the Enable is important only for the positive Clock Transition when the counter is in state 1100.



APPLICATIONS INFORMATION

The primary application of these devices is as a high-speed variable modulus prescaler in the divide by N section of a phase-locked loop synthesizer used as the local oscillator of two-way radios. The theory and advantages of variable modulus prescaling, along with typical applications, are covered in Motorola's "Electronic Tuning Address Systems" (SG72).

Proper VHF termination techniques should be followed when the clock is separated from the prescaler by any appreciable distance.

In their basic form, these devices will divide by 5/6, 8/9, or 10/11. Division by 5, 8, or 10 occurs when any one or all of the five gate inputs E1 through E5 are high. Division by 6, 9, or 11 occurs when all inputs E1 through E5 are low. (Unconnected MTTL inputs are normally high, unconnected MECL inputs are normally low). With the addition of extra parts, many different division configurations may be obtained (20/21, 40/41, 50/51, 100/101, etc.) A few of the many configurations are shown below, only for the ML12513

FIGURE 8 — DIVIDE BY 10/11 (ML12513)

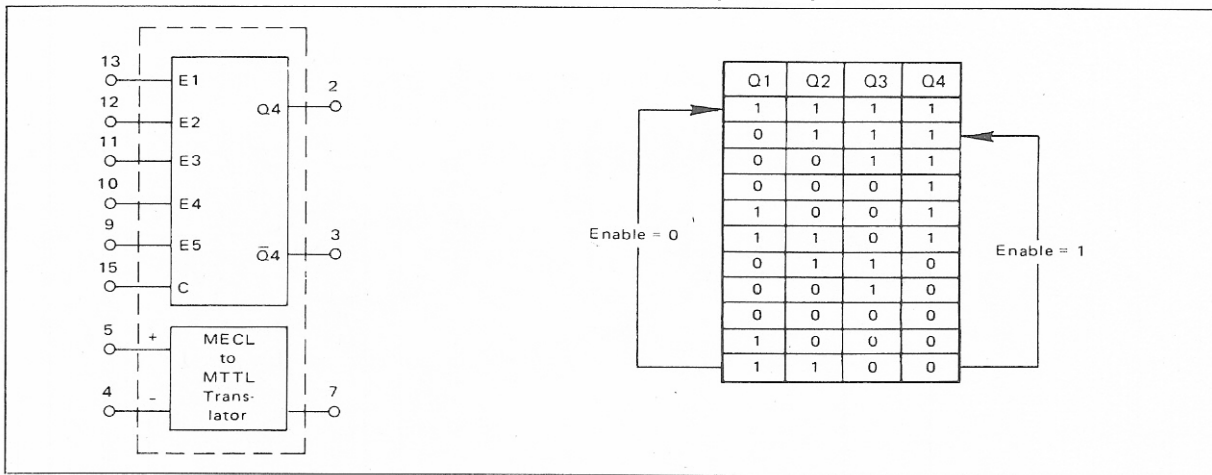


FIGURE 9 — DIVIDE BY 20/21 (ML12513)

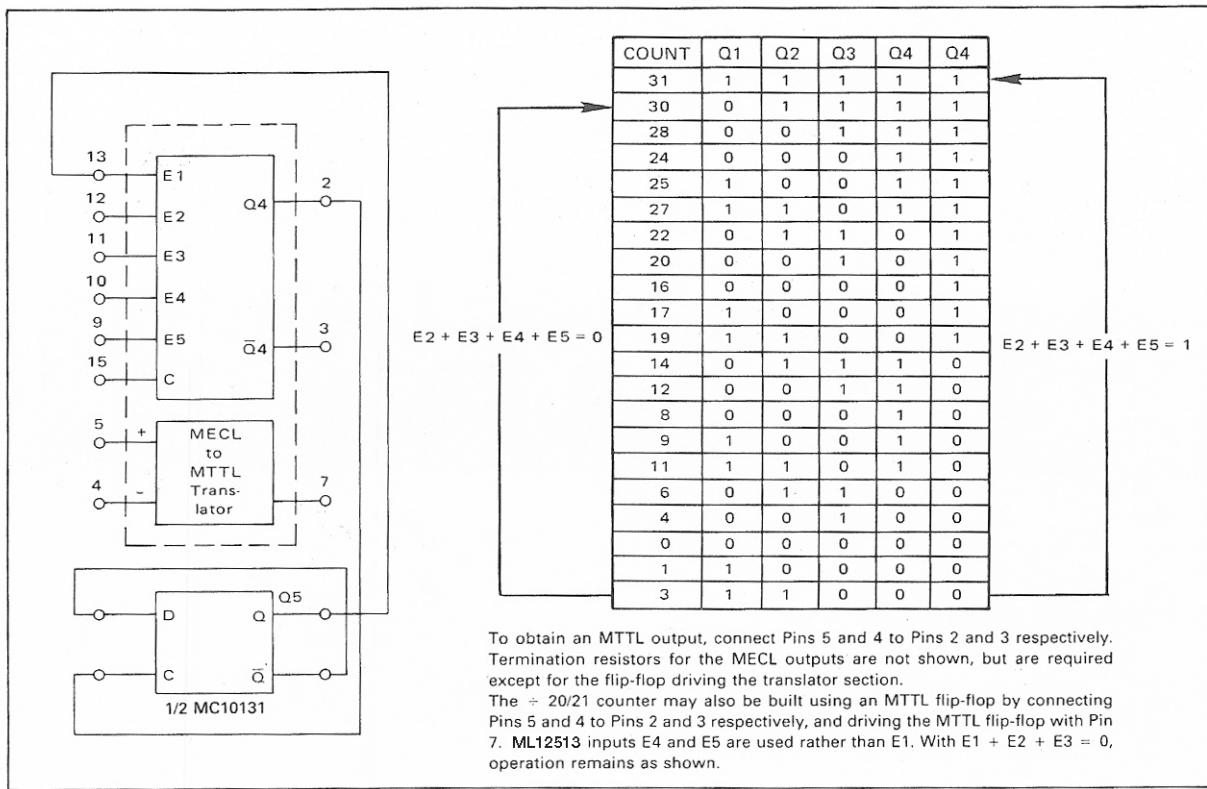
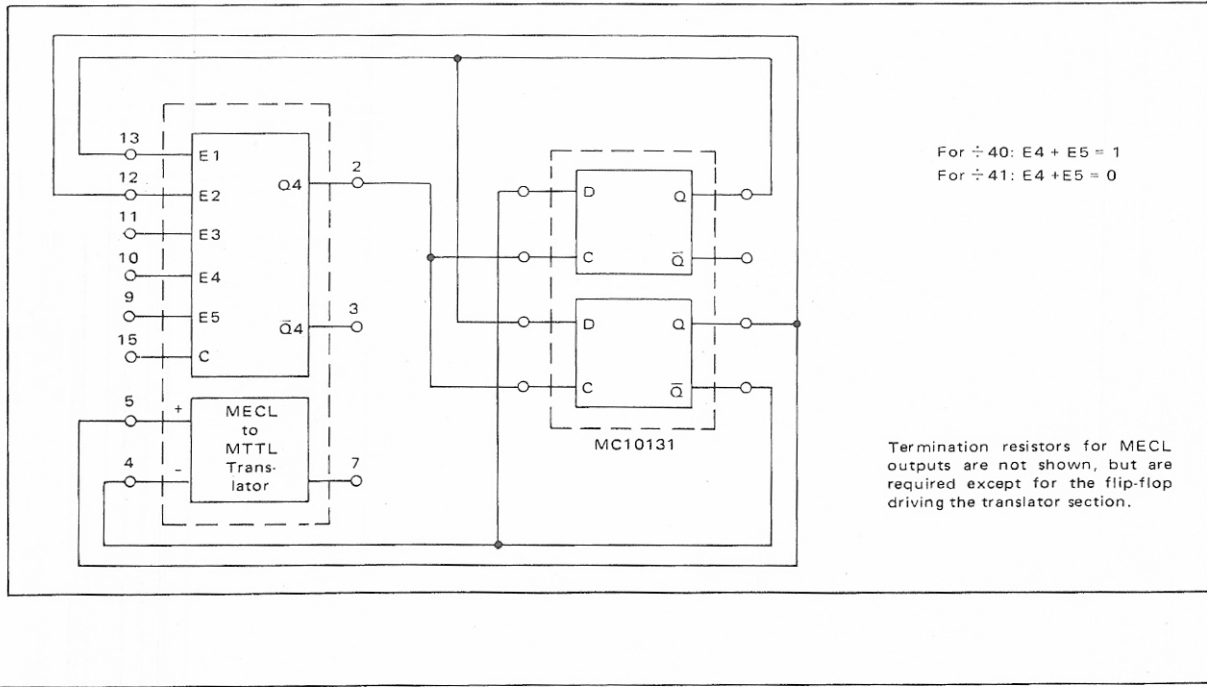
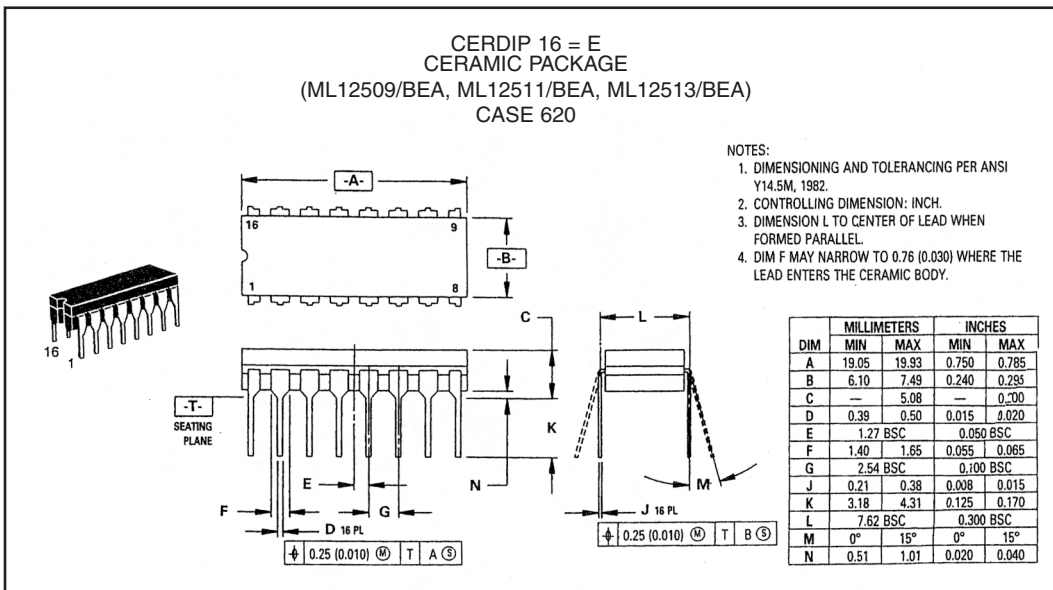


FIGURE 10 — DIVIDE BY 40/41 (ML12513)



OUTLINE DIMENSIONS

CERDIP 16 = E
 CERAMIC PACKAGE
 (ML12509/BEA, ML12511/BEA, ML12513/BEA)
 CASE 620



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